

SLOVENSKI STANDARD
SIST EN 62884-1:2017

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Merilne tehnike za piezoelektrične, dielektrične in elektrostatične oscilatorje - 1.
del: Osnovne merilne metode (IEC 62884-1:2017)

Measurement techniques of piezoelectric, dielectric and electrostatic oscillators - Part 1:
Basic methods for the measurement (IEC 62884-1:2017)

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Ta slovenski standard je istoveten z: ^{SIST EN 62884-1:2017}**EN 62884-1:2017**
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EUROPEAN STANDARD

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Measurement techniques of piezoelectric,
dielectric and electrostatic oscillators -
Part 1: Basic methods for the measurement
(IEC 62884-1:2017)

Techniques de mesure des oscillateurs piézoélectriques,
diélectriques et électrostatiques -
Partie 1 : Méthodes fondamentales pour le mesurage
(IEC 62884-1:2017)

Messverfahren für piezoelektrische, dielektrische
und elektrostatische Oszillatoren -
Teil 1: Grundlegende Messverfahren
(IEC 62884-1:2017)

This European Standard was approved by CENELEC on 2017-07-13. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

EN 62884-1:2017**European foreword**

The text of document 49/1187A/CDV, future edition 1 of IEC 62884-1, prepared by IEC/TC 49 "Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62884-1:2017.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2018-04-13
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2020-07-13

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The text of the International Standard IEC 62884-1:2017 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60122-1:2002	NOTE	Harmonized as EN 60122-1:2002 (not modified).
IEC 60679-3:2012	NOTE	Harmonized as EN 60679-3:2013 (not modified).
IEC 60679-4	NOTE	Harmonized as EN 60679-4.
IEC 60679-5	NOTE	Harmonized as EN 60679-5.
IEC 60749-26	NOTE	Harmonized as EN 60749-26.
IEC 60749-27	NOTE	Harmonized as EN 60749-27.
IEC 61000-4-2	NOTE	Harmonized as EN 61000-4-2.
IEC 61019-1:2004	NOTE	Harmonized as EN 61019-1:2005 (not modified).
IEC 61019-2:2005	NOTE	Harmonized as EN 61019-2:2005 (not modified).
IEC 61837-1:2012	NOTE	Harmonized as EN 61837-1:2012 (not modified).
IEC 61837-2:2011	NOTE	Harmonized as EN 61837-2:2011 (not modified).
IEC 61837-4:2015	NOTE	Harmonized as EN 61837-4:2015 (not modified).
ISO 80000-4:2006	NOTE	Harmonized as EN ISO 80000-4:2013 (not modified).

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60027	series	Letter symbols to be used in electrical technology	EN 60027	series
IEC 60050-561	-	International electrotechnical vocabulary - Part 561: Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection	-	-
IEC 60068-1	2013	Environmental testing - Part 1: General and guidance	EN 60068-1	2014
IEC 60068-2-1	-	Environmental testing - Part 2-1: Tests - Test A: Cold	EN 60068-2-1	-
IEC 60068-2-2	-	Environmental testing - Part 2-2: Tests - Test B: Dry heat	EN 60068-2-2	-
IEC 60068-2-6	-	Environmental testing - Part 2-6: Tests - Test Fc: Vibration (sinusoidal)	EN 60068-2-6	-
IEC 60068-2-7	-	Basic environmental testing procedures - Part 2-7: Tests - Test Ga and guidance: Acceleration, steady state	EN 60068-2-7	-
IEC 60068-2-10	2005	Environmental testing - Part 2-10: Tests - Test J and guidance: Mould growth	EN 60068-2-10	2005
IEC 60068-2-13	-	Basic environmental testing procedures - Part 2-13: Tests - Test M: Low air pressure	EN 60068-2-13	-
IEC 60068-2-14	-	Environmental testing - Part 2-14: Tests - Test N: Change of temperature	EN 60068-2-14	-
IEC 60068-2-17	1994	Basic environmental testing procedures - Part 2-17: Tests - Test Q: Sealing	EN 60068-2-17	1994

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<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60068-2-20	-	Environmental testing - Part 2-20: Tests - Test T: Test methods for solderability and resistance to soldering heat of devices with leads	EN 60068-2-20	-
IEC 60068-2-21	-	Environmental testing - Part 2-21: Tests - Test U: Robustness of terminations and integral mounting devices	EN 60068-2-21	-
IEC 60068-2-27	-	Environmental testing - Part 2-27: Tests - Test Ea and guidance: Shock	EN 60068-2-27	-
IEC 60068-2-30	-	Environmental testing - Part 2-30: Tests - Test Db: Damp heat, cyclic (12 h + 12 h cycle)	EN 60068-2-30	-
IEC 60068-2-31	-	Environmental testing - Part 2-31: Tests - Test Ec: Rough handling shocks, primarily for equipment-type specimens	EN 60068-2-31	-
IEC 60068-2-45	-	Basic environmental testing procedures - Part 2-45: Tests - Test XA and guidance: Immersion in cleaning solvents	EN 60068-2-45	-
IEC 60068-2-52	-	Environmental testing - Part 2-52: Tests - Test Kb: Salt mist, cyclic (sodium chloride solution)	EN 60068-2-52	-
IEC 60068-2-58	-	Environmental testing - Part 2-58: Tests - Test Td: Test methods for solderability, resistance to dissolution of metallization and to soldering heat of surface mounting devices (SMD)	EN 60068-2-58	-
IEC 60068-2-64	-	Environmental testing - Part 2-64: Tests - Test Fh: Vibration, broadband random and guidance	EN 60068-2-64	-
IEC 60068-2-78	-	Environmental testing - Part 2-78: Tests - Test Cab: Damp heat, steady state	EN 60068-2-78	-
IEC 60469	-	Transitions, pulses and related waveforms - Terms, definitions and algorithms	EN 60469	-
IEC 60617-DB	-	Graphical symbols for diagrams	-	-
IEC 60679-1	2017	Piezoelectric, dielectric and electrostatic oscillators of assessed quality - Part 1 : Generic specification	EN 60679-1	— ¹⁾
ISO 80000-1	-	Quantities and units - Part 1: General	EN ISO 80000-1	-

1) To be published.



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**Measurement techniques of piezoelectric, dielectric and electrostatic oscillators –
Part 1: Basic methods for the measurement**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**MEASUREMENT TECHNIQUES OF PIEZOELECTRIC,
DIELECTRIC AND ELECTROSTATIC OSCILLATORS –****Part 1: Basic methods for the measurement**

FOREWORD

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International Standard IEC 62884-1 has been prepared by IEC technical committee 49: Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection.

The text of this International Standard is based on the following documents:

CDV	Report on voting
49/1187A/CDV	49/1200/RVC

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62884 series, published under the general title *Measurement techniques of piezoelectric, dielectric and electrostatic oscillators*, can be found on the IEC website.

A bilingual version of this publication may be issued at a later date.

IMPORTANT – The 'colour inside' logo on the cover page of this publication indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.

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MEASUREMENT TECHNIQUES OF PIEZOELECTRIC, DIELECTRIC AND ELECTROSTATIC OSCILLATORS –

Part 1: Basic methods for the measurement

1 Scope

This part of IEC 62884 specifies the measurement techniques for piezoelectric, dielectric and electrostatic oscillators, including Dielectric Resonator Oscillators (DROs) and oscillators using FBAR (hereinafter referred to as "Oscillator").

NOTE Dielectric Resonator Oscillators (DROs) and oscillators using FBAR are under consideration.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60027 (all parts), *Letter symbols to be used in electrical technology*

IEC 60050-561, *International electrotechnical vocabulary – Part 561: Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection*. Available at <http://www.electropedia.org>

IEC 60068-1:2013, *Environmental testing – Part 1: General and guidance*

IEC 60068-2-1, *Environmental testing – Part 2-1: Tests – Test A: Cold*

IEC 60068-2-2, *Environmental testing – Part 2-2: Tests – Test B: Dry heat*

IEC 60068-2-6, *Environmental testing – Part 2-6: Tests – Test Fc: Vibration (sinusoidal)*

IEC 60068-2-7, *Basic environmental testing procedures – Part 2-7: Tests – Test Ga and guidance: Acceleration, steady state*

IEC 60068-2-10:2005, *Environmental testing – Part 2-10: Tests – Test J and guidance: Mould growth*

IEC 60068-2-13, *Basic environmental testing procedures – Part 2-13: Tests – Test M: Low air pressure*

IEC 60068-2-14, *Environmental testing – Part 2-14: Tests – Test N: Change of temperature*

IEC 60068-2-17:1994, *Basic environmental testing procedures – Part 2-17: Tests – Test Q: Sealing*

IEC 60068-2-20, *Environmental testing – Part 2-20: Tests – Test T: Test methods for solderability and resistance to soldering heat of devices with leads*

IEC 60068-2-21, *Environmental testing – Part 2-21: Tests – Test U: Robustness of terminations and integral mounting devices*

IEC 60068-2-27, *Environmental testing – Part 2-27: Tests – Test Ea and guidance: Shock*

IEC 60068-2-30, *Environmental testing – Part 2-30: Tests – Test Db: Damp heat, cyclic (12 h + 12 h cycle)*

IEC 60068-2-31, *Environmental testing – Part 2-31: Tests – Test Ec: Rough handling shocks, primarily for equipment-type specimens*

IEC 60068-2-45, *Basic environmental testing procedures – Part 2-45: Tests – Test XA and guidance: Immersion in cleaning solvents*

IEC 60068-2-52, *Environmental testing – Part 2-52: Tests – Test Kb: Salt mist, cyclic (sodium, chloride solution)*

IEC 60068-2-58, *Environmental testing – Part 2-58: Tests – Test Td: Test methods for solderability, resistance to dissolution of metallization and to soldering heat of surface mounting devices (SMD)*

IEC 60068-2-64, *Environmental testing – Part 2-64: Tests – Test Fh: Vibration, broadband random and guidance*

IEC 60068-2-78, *Environmental testing – Part 2-78: Tests – Test Cab: Damp heat, steady state*

IEC 60469, *Transitions, pulses and related waveforms – Terms, definitions and algorithms*

IEC 60617, *Graphical symbols for diagrams*. Available at <http://std.iec.ch/iec60617>

IEC 60679-1:2017, *Piezoelectric, dielectric and electrostatic oscillators of assessed quality – Part 1: Generic specification*

ISO 80000-1, *Quantities and units – Part 1: General*

Where any discrepancies occur for any reason, documents shall rank in the following order of precedence:

- detail specification;
- sectional specification;
- generic specification;
- any other international documents (for example of the IEC) to which reference is made.

The same order of precedence shall apply to equivalent national documents.

3 Terms and definitions

3.1 General

Units, graphical symbols, letter symbols and terminology shall, wherever possible, be taken from the following standards:

- IEC 60027;
- IEC 60050-561;
- IEC 60469;
- IEC 60617;
- ISO 80000-1.